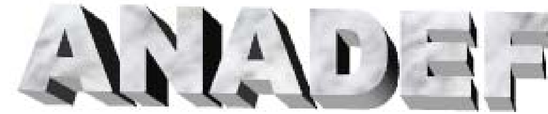

Optical probing techniques: Laser Voltage Probing, Time Resolved Emission & Time Resolved Imaging

Chairman Frank Zachariasse, NXP, Nijmegen

13:10-13:20	Dynamic Emission microscopy background (Philippe Perdu CNES Toulouse)
13:20-13:40	Functional analysis with dynamic emission microscopy (Jerome Di Battista, Thales France)
13:40-14:00	LVP and Frequency Mapping (Larry Ross, Semicaps)
14:00-14 :20	Laser Voltage Probing & Imaging (Herve Deslandes DCGSystems)
14:20-14:40	Facing the poor optical resolution and the sensor sensitivity limitation challenges for TRE probing (Sylvain Dudit, ST Crolles)
14:40-15:00	Design visibility enhancement for failure analysis (Etienne Auvray, ST Grenoble)
15:00-15:20	Questions and answers (Moderator Abdel Firiti, FREESCALE Toulouse)